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D A Minkov¹, G M Gavrilov¹, G V Angelov², J M D Moreno³, C G Vazquez³, S M F Ruano⁴, and E Marquez⁵

¹ College of Energy and Electronics, Technical University of Sofia, bul. Bulgaria 31, 2140 Botevgrad, Bulgaria

² Department of Microelectronics, Faculty of Electronics Engineering and Technologies, Technical University of Sofia, bul. Kliment Ohridski 8, Sofia 1000, Bulgaria

³ Department of Mathematics, Faculty of Science, University of Cadiz, 11510 Puerto Real, Cadiz, Spain

⁴ Photovoltaic Solar Energy Unit, CIEMAT, Avenida Complutense 40, 28040 Madrid, Spain

⁵ Department of Condensed-Matter Physics, Faculty of Science, University of Cadiz, 11510 Puerto Real, Cadiz, Spain

Corresponding Author: D.A. Minkov, email: dorianminkov@yahoo.com, tel: (+359) 0885948710

Abstract: The spectroscopic ellipsometry is the main tool for optical characterization of a thin film in its spectral region of strong absorption, where its transmittance spectrum does not contain interference pattern. The envelope method (EM) is the main tool for accurate optical characterisation of a thin film with thickness typically in the range [500, 5000] nm on a substrate.

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